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**Structure and photocatalytic properties of Ti<sub>1-x</sub>W<sub>x</sub>O<sub>2</sub> sputtered thin films**Grégory Abadias<sup>1</sup>, Aldo Gago-Rodriguez<sup>2</sup>, Nicolas Alonso-Vante<sup>2</sup><sup>1</sup>University of Poitiers, Chasseneuil-Futuroscope, France <sup>2</sup>LACCO, Université de Poitiers-CNRS, Poitiers, France

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The ability of titanium dioxide (TiO<sub>2</sub>) compounds to generate electron-hole pairs under UV absorption has motivated many investigations due to its widespread applications in the energy and environment fields, such as antimicrobial, antifogging, or self-cleaning coatings, as well as for air or water purification and sterilization. In order to improve its photocatalytic activity in the visible-light spectrum, doping with metals as substitution for Ti cations or N or C as substitution for O has been used. Different routes can be selectively employed to achieve such doping, e.g., chemical, physical deposition processes, or ion implantation.

We report in the present work on the effect of W doping on the structure, phase stability and photocatalytic properties of TiO<sub>2</sub> thin films grown by magnetron sputtering. For this purpose, Ti<sub>1-x</sub>W<sub>x</sub>O<sub>y</sub> films with varying W contents between 0 and 0.5 were deposited by magnetron co-sputtering from Ti and W targets in either pure Ar or mixed Ar+O<sub>2</sub> plasma discharges on Si and on conducting glass substrates (SnO<sub>2</sub>:F). For reactive sputtering, the characteristics of the sputtering mode were determined by recording the evolutions of the O<sub>2</sub> partial pressure and target voltage vs. O<sub>2</sub> flow. For both reactive and unreactive growth conditions, films were subsequently annealed at 550°C for 3h under vacuum or under air to promote phase crystallisation in the rutile or anatase structures, as characterized using X-ray Diffraction. While Ti<sub>1-x</sub>W<sub>x</sub> alloys grown by unreactive sputtering were unstable after annealing, Ti<sub>1-x</sub>W<sub>x</sub>O<sub>y</sub> films grown by reactive sputtering crystallized after annealing in the rutile and anatase phases for low W contents, with a distorted lattice cell due to W incorporation. For larger W content, the formation of WO<sub>3</sub> phase was evidenced. The photoelectrochemical properties of the different films were further investigated in 0.5M H<sub>2</sub>SO<sub>4</sub> and 0.1M NaOH electrolytes. It was found an enhanced activity for water electrolysis of low tungsten doping contents, such as x=0.18 in Ti<sub>(1-x)</sub>W<sub>x</sub>O<sub>2</sub> as compared to non doped TiO<sub>2</sub>.

**Keywords**TiO<sub>2</sub>

W doping

Sputtering